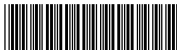


**Search Notes****Application/Control No.**

10/661,638

**Examiner**

LOIS ZHENG

**Applicant(s)/Patent under  
Reexamination**

HIRAIWA ET AL.

**Art Unit**

1733

**SEARCHED**

Class	Subclass	Date	Examiner
204	263	10/12/2011	LLZ
204	266	10/12/2011	LLZ
204	275.1	10/12/2011	LLZ
204	277	10/12/2011	LLZ
204	279	10/12/2011	LLZ
205	359	10/12/2011	LLZ
205	411	10/12/2011	LLZ
205	459	10/12/2011	LLZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
204	279	10/12/2011	LLZ
204	275.1	10/12/2011	LLZ
205	411	10/12/2011	LLZ

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
inventorship search	10/12/2011	LLZ
Updated EAST search	10/12/2011	LLZ